

**July 2011** 

## FDB390N15A

# N-Channel PowerTrench<sup>®</sup> MOSFET 150V, 27A, 39m $\Omega$

#### **Features**

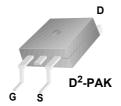
- $R_{DS(on)}$  = 33.5m $\Omega$  ( Typ.)@  $V_{GS}$  = 10V,  $I_D$  = 27A
- · Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low  $R_{DS(\text{on})}$
- · High Power and Current Handling Capability
- · RoHS Compliant

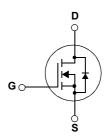
## **Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advance PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

## **Application**

- · DC to DC Converters
- · Synchronous Rectification for Telecommunication PSU
- Battery Charger
- AC Motor Drives and Uninterruptible Power Supplies
- Off-line UPS





## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter		Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage	Drain to Source Voltage		150	V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
1	Drain Current	- Continuous (T <sub>C</sub> = 25°C,Silicon Limited)		27	А
ID	Drain Current	- Continuous (T <sub>C</sub> = 100°C,Silicon	Limited)	19	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	108	Α
E <sub>AS</sub>	Single Pulsed Avalanche Ene	ergy	(Note 2)	78	mJ
dv/dt	Peak Diode Recovery dv/dt	Peak Diode Recovery dv/dt (Note 3)		6.0	V/ns
D	Davier Dissipation	$(T_C = 25^{\circ}C)$		75	W
$P_{D}$	Power Dissipation	- Derate above 25°C		0.5	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temp	erature Range		-55 to +175	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

#### **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	-C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB390N15A	FDB390N15A	D2-PAK	330mm	24mm	800

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	150	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.1	-	V/°C
1	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 120V, V <sub>GS</sub> = 0V	-	-	1	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 120V, T_C = 150^{\circ}C$	-	-	500	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA

## **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 27A$	-	33.5	39	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10V, I <sub>D</sub> = 27A (Note 4)	-	33	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	757777		-	965	1285	pF
Coss	Output Capacitance	$V_{DS} = 75V, V_{GS} = 0V$ = 1MHz	Ī	-	96	130	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/12	Ī	-	5.8	-	pF
C <sub>oss(er)</sub>	Energy Related Output Capacitance	$V_{DS} = 75V, I_D = 27A$			169	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			-	14.3	18.6	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DS</sub> = 75V, I <sub>D</sub> = 27A	Ī		5.0	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	V <sub>GS</sub> = 10V	Ī	-	2.0	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		(Note 4,5)	-	3.5	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open,f = 1MHz		-	1.4	-	Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	14	38	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 75V, I_D = 27A$		-	10	30	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10V, $R_{GEN}$ = 4.7 $\Omega$		-	20	50	ns
t <sub>f</sub>	Turn-Off Fall Time	(No	ote 4,5)	-	5	20	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	27	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	108	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 27A	-	-	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 27A, V <sub>DD</sub> = 75V	-	63	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$ (Note 4)	-	131	-	nC

#### Notes

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. Starting  $T_J$  = 25°C, L = 3 mH,  $I_{SD}$  = 7.2 A
- 3.  $I_{SD} \le 27 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J$  =  $25^{\circ}C$
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Char acteristics**

Figure 1. On-Region Characteristics

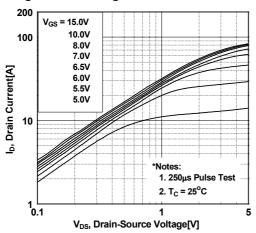


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

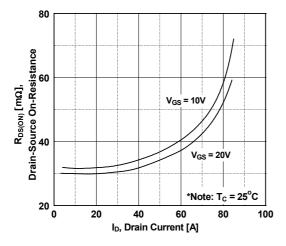
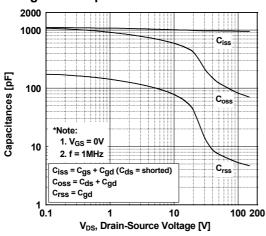


Figure 5. Capacitance Characteristics



**Figure 2. Transfer Characteristics** 

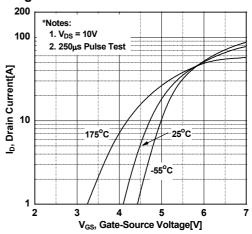


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

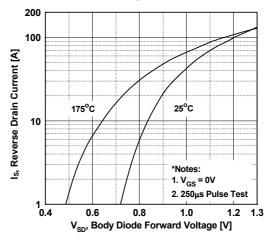
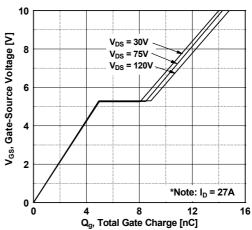


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

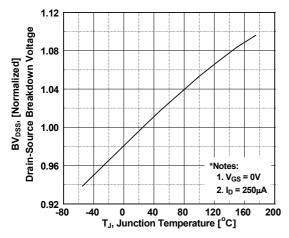


Figure 9. Maximum Safe Operating Area

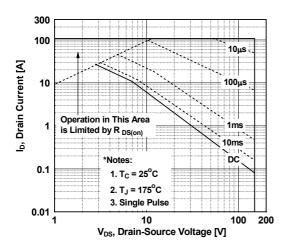


Figure 11. Eoss vs.Drain to Source Voltage

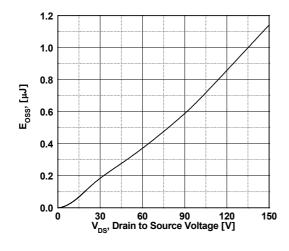


Figure 8. On-Resistance Variation vs. Temperature

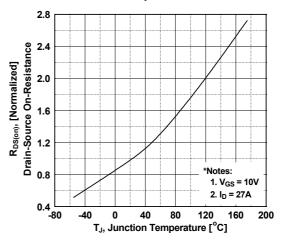


Figure 10. Maximum Drain Current vs. Case Temperature

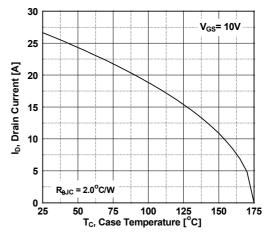
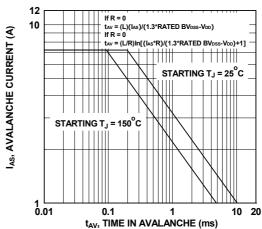
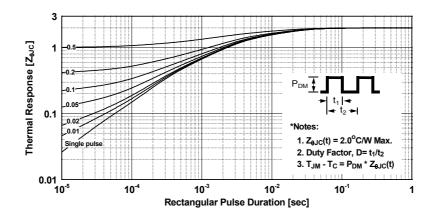


Figure 12. Unclamped Inductive Switching Capability

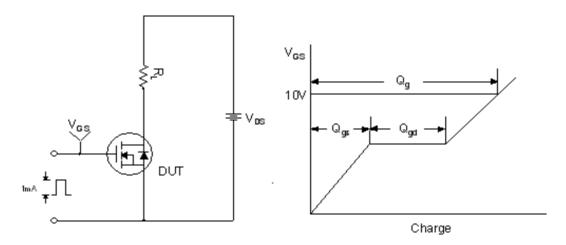


## **Typical Performance Characteristics** (Continued)

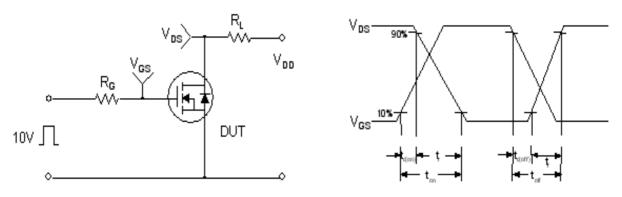




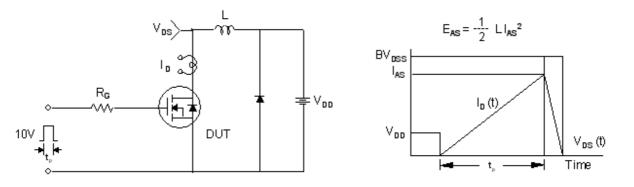
## **Gate Charge Test Circuit & Waveform**



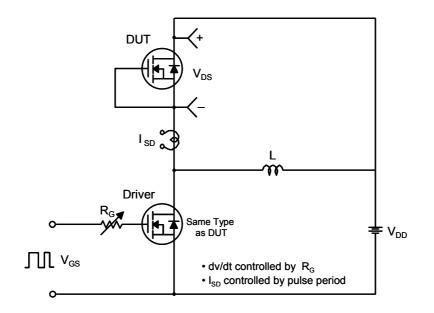
## **Resistive Switching Test Circuit & Waveforms**

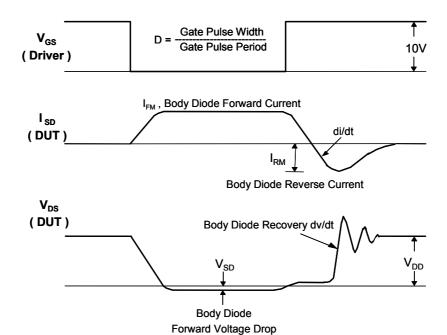


**Unclamped Inductive Switching Test Circuit & Waveforms** 



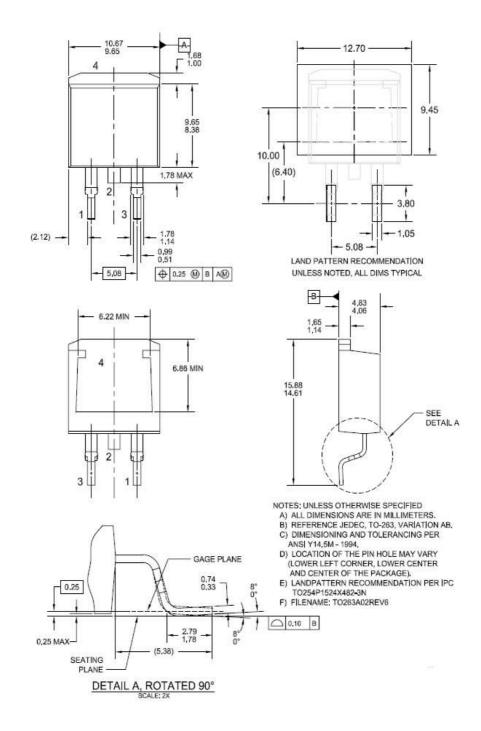
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





## **Mechanical Dimensions**

## D<sup>2</sup>PAK



Dimensions in Millimeters





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